

10/544178

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Attorney Docket: 061063-0317066  
Client Reference: OSP-18862

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re National Stage Application of  
PCT/JP2003/0132171 to OKUBO ET AL.  
Application No.:

Confirmation Number:  
Group Art Unit:

Filed: August 1, 2005

Examiner:

Title: INSPECTION METHOD, MANUFACTURING METHOD OF PIECE FOR  
ANALYSIS, ANALYSIS METHOD, ANALYZER, MANUFACTURING METHOD OF SOI  
WAFER, AND SOI WAFER

PRELIMINARY AMENDMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Before beginning examination, please amend the above-identified National Stage application as follows:

IN THE TITLE:

Please delete the Title of the Invention as presented in the International Stage and insert the following title therefor:

INSPECTION METHOD, MANUFACTURING METHOD OF PIECE FOR ANALYSIS,  
ANALYSIS METHOD, ANALYZER, MANUFACTURING METHOD OF SOI WAFER,  
AND SOI WAFER